

Notice of References Cited	Application/Control No. 10/080,540	Applicant(s)/Patent Under Reexamination MIZUMURA ET AL.	
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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
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	C	US-			
	D	US-			
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	F	US-			
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